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Components, Packaging, and Manufacturing Technology, Part B: Advanced Packaging, IEEE Transactions on [see also Components, Hybrids, and Manufacturing Technology, IEEE Transactions on] , Volume: 19 , Issue: 2 , March 1996

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AUTOTESTCON '99. IEEE Systems Readiness Technology Conference, 1999. IEEE , 30 Aug.-2 Sept. 1999

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EUROMICRO Conference, 1999. Proceedings. 25th , Volume: 2 , 8-10 Sept. 1999. Pages:105 - 112 vol.2

[\[Abstract\]](#)   [\[PDF Full-Text \(84 KB\)\]](#)   IEEE CNF**4 The PURE family of object-oriented operating systems for deeply**

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*Beuche, D.; Guerrouat, A.; Papajewski, H.; Schroder-Preikschat, W.; Spinczyk, U.;*

Object-Oriented Real-Time Distributed Computing, 1999. (ISORC '99) Proceed  
2nd IEEE International Symposium on , 2-5 May 1999

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